

# Search Notes



Application/Control No.

10/651,137

Examiner

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Applicant(s)/Patent under Reexamination

KOPF ET AL.

Art Unit

2839

## SEARCHED

Class	Subclass	Date	Examiner
Search	Update	10/05	hnh

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
385	77	10/05	hnh
385	139	↓	↓

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Interference Search Done	10/05	hnh